

## **TEST REPORT**

Report No. A-373-20-A

Date of Issue: 19 May 2021

Department of Defense Interface Standard Military Standard 461 G

This test report is to certify that the device was tested according to the requirements of the above.

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1. Applicant								
Company Name		: Mobile Solutions Business Division, Connected Solutions Company, Panasonic Corporation						
Address		: ytv Kyobashi Building, 2-2-33 Shiromi, Chuo-ku, Osaka 540-8553, Japan						
2. Identifica	tion of Tested Dev	ice						
Device Name		: Personal Computer						
Model Number		: FZ-G2	: FZ-G2					
Serial Number		: Tablet: 0LTSA00556, Base: 0LTSA00612						
Trade Name		: Panaso	: Panasonic					
Type of Test		: ■ Product Validation □ Design Validation □ Development Purpose						
Test Plan Number		: KEC-G111F A-373-20-A 2021-4-2						
Modification of Test Plan : ■No □Yes (refer to deviation information in this report)								
3. Test Item	s and Procedure							
CE101	CE101 conducted emissions, audio frequency currents, power lead			its, power leads.	Pass	$\Box$ Fail	□N/A	
CE102	conducted emissions, radio frequency potential, power leads.			ial, power leads.	Pass	$\Box$ Fail	□N/A	
CS101	conducted susceptibility, power leads.			9.2	Pass	$\Box$ Fail	□N/A	
CS114	• • • • • • • • • • • • • • • • • • • •			1.	Pass	□Fail	□N/A	
CS115	conducted susceptibility, bulk cable injection, impulse exc			n, impulse excitation.	Pass	□Fail	□N/A	
CS116	conducted susceptibility, damped sinusoidal transients, cables and power leads.				■ Pass	$\Box$ Fail	□N/A	
CS117	conducted susceptibility, lightning induced transients, cables and power leads.						■N/A (*3)	
CS118	personnel borne electrostatic discharge.				Pass	□Fail	□N/A	
RE101	radiated emissions, magnetic field.				Pass	□Fail	□N/A	
RE102	radiated emissions, electric field.				Pass	□Fail	□N/A	
RS101	radiated susceptibility, magnetic field.				Pass	□Fail	□N/A	
RS103							□N/A	
Refer the below reason(s) with respect to the decision and justification not to test.  (*1) DUT Specification (*2) Request of Applicant (*3) According to Test Plan (*4) Not Included in This Report								
KEC Electronic Industry Development Center Testing Division 3-2-2, Hikari-dai, Seika-cho, Soraku-gun, Kyoto 619-0237 Japan								
Test Engineer(s)								

Hironori Okamoto



Approved by

Ikuya Minematsu / Division Manager

KEC Testing Division Report Version: A